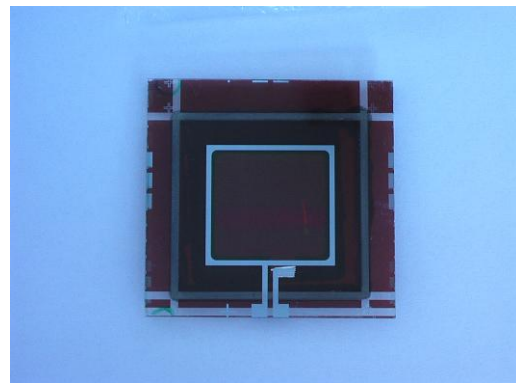


## Additional setups and results

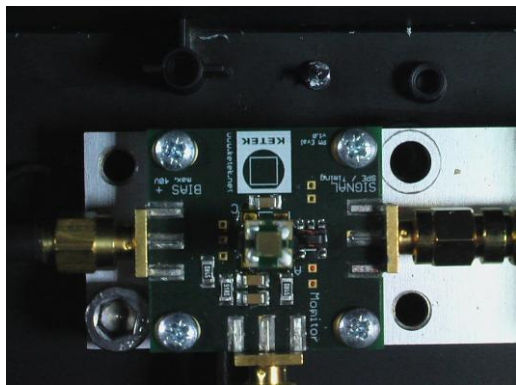


a

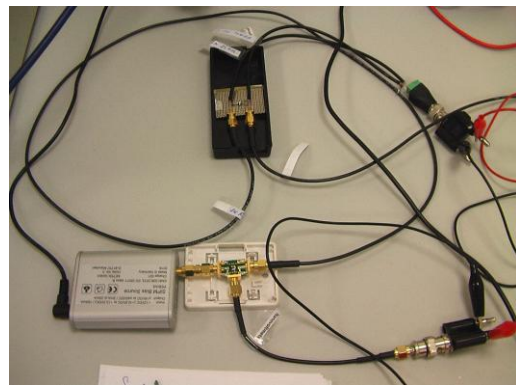


b

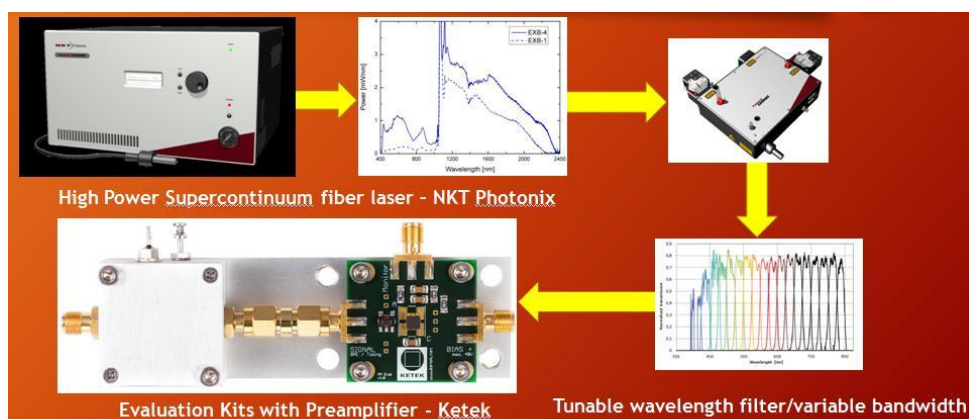
Fig 1 Samples of the investigated devices: a – SiPMs produced by Ketek (Germany); organic solar cells produced by Holst Centre – Solliance, TNO (The Netherlands).



a

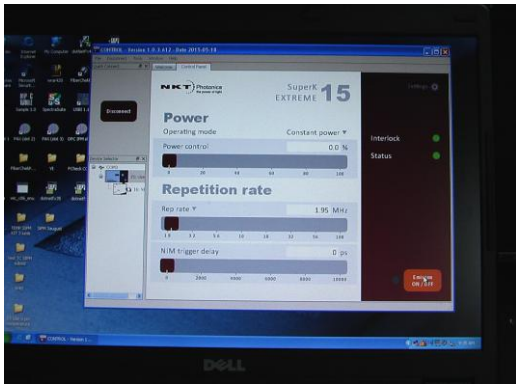


b

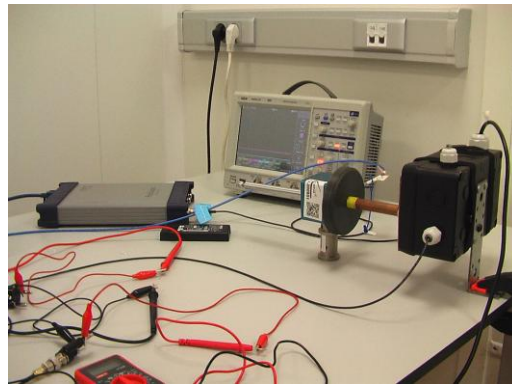


c

Fig. 2 Measuring setups for the characterization of SiPMs: a – Ketek SiPM testing board; b – SiPM power supply circuit; c – setup for variable wavelength excitation of the SiPM with a tunable ps laser source.



a



b

Fig. 3 Tunable laser control interface (a); data acquisition setup using the Picoscope instrument.

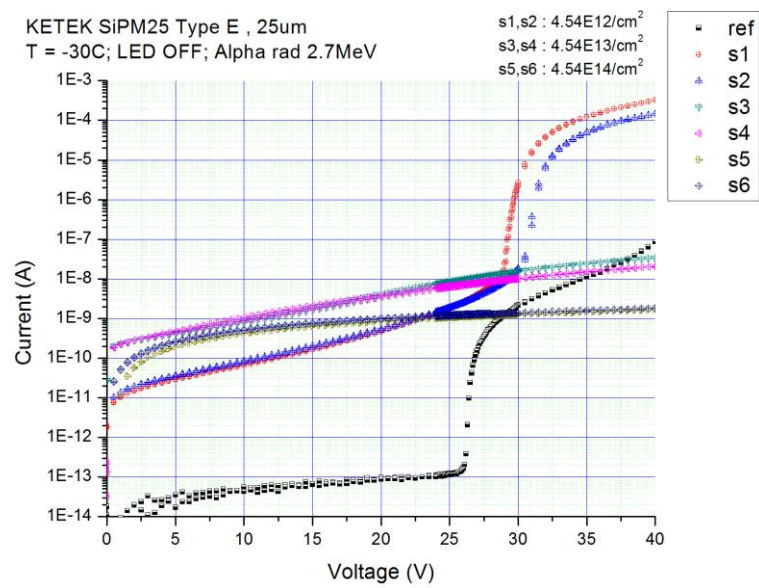


Fig. 4 SiPM I-V characteristic degradation under alpha particles irradiation.

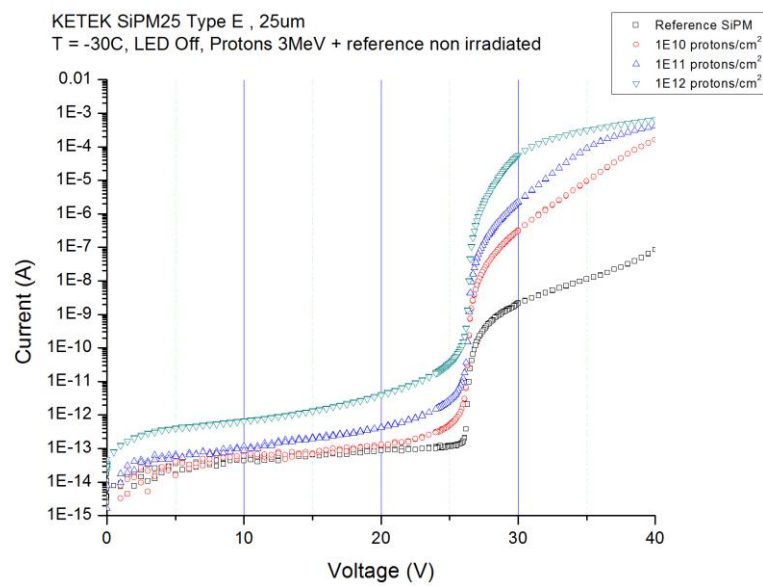


Fig. 5 SiPM I-V characteristic degradation under proton irradiation.

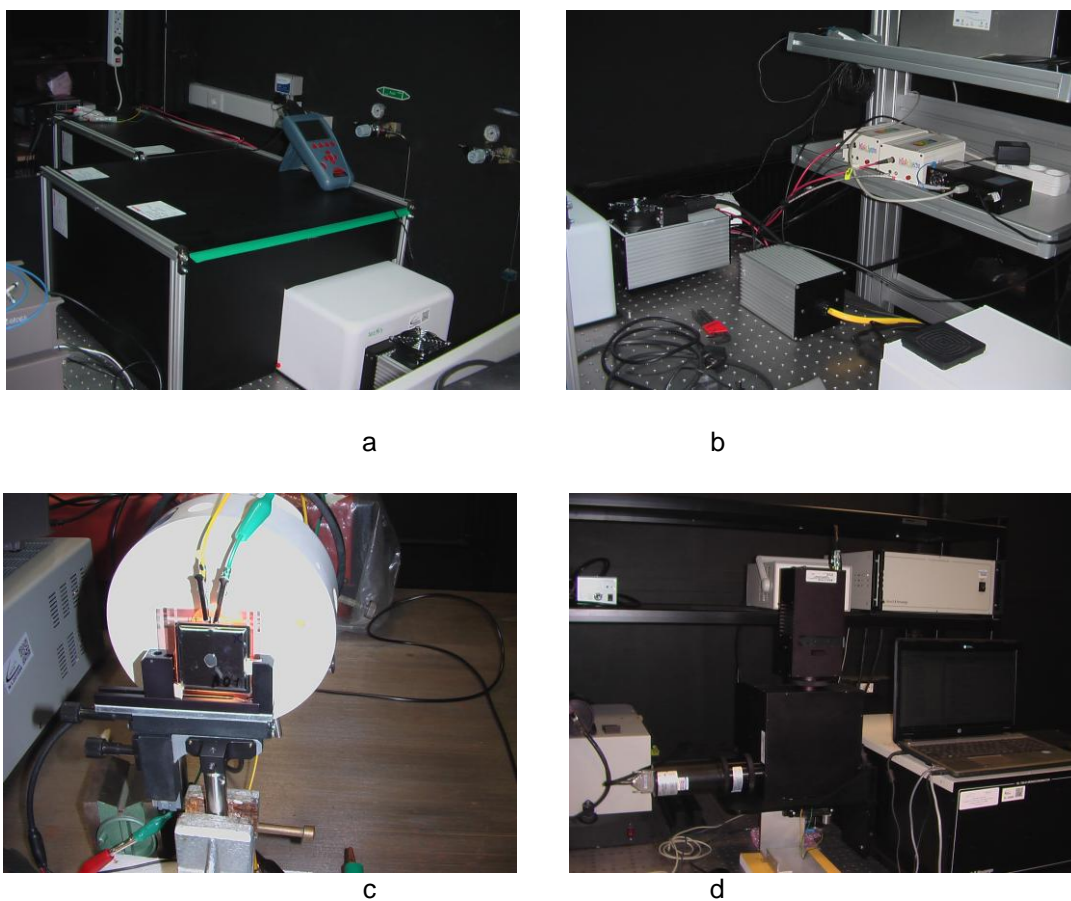


Fig.7 The solar simulator (a) and its characterization setup (b); c and d – setups for the evaluation of solar cells.

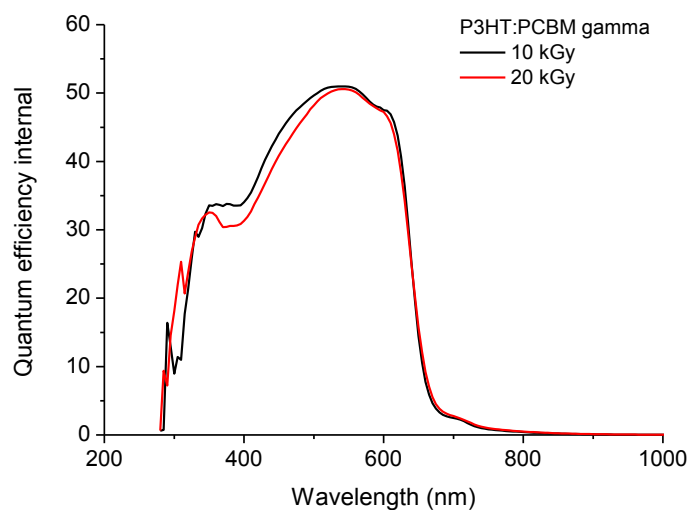
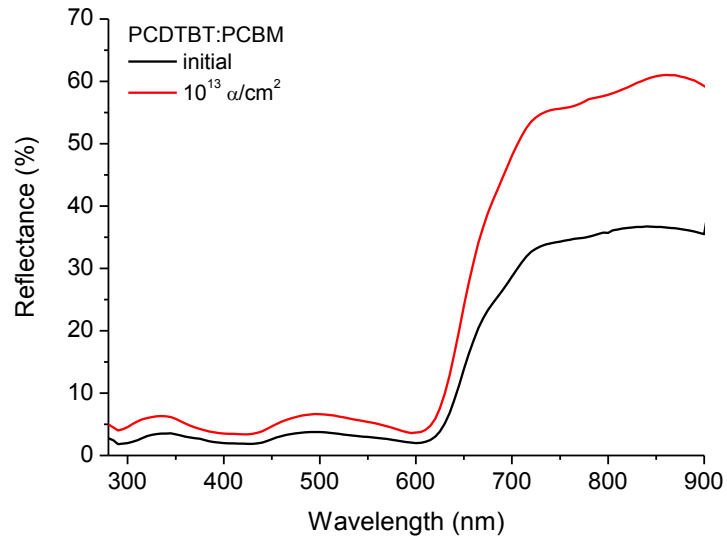
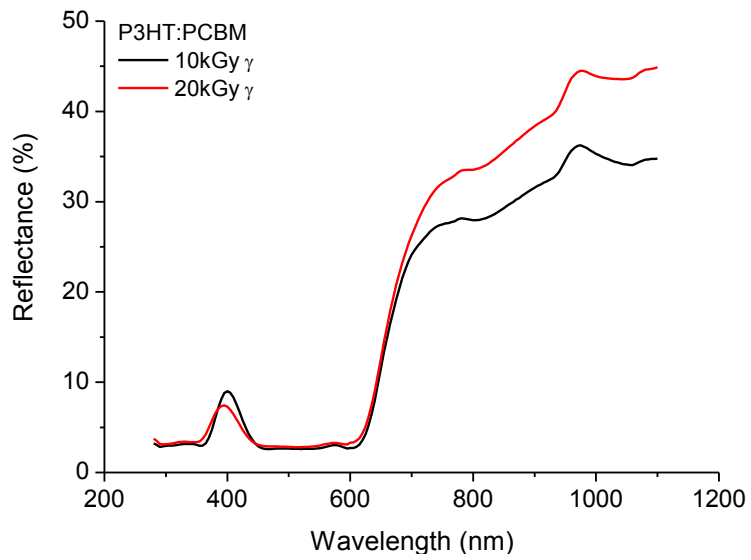


Fig.8 Change of the internal quantum efficiency of an organic solar cell under gamma ray irradiation.



a



b

Fig. 9. Modification of two organic solar cells diffused spectral reflectance for: a – alpha particles irradiation; b – gamma ray irradiation.

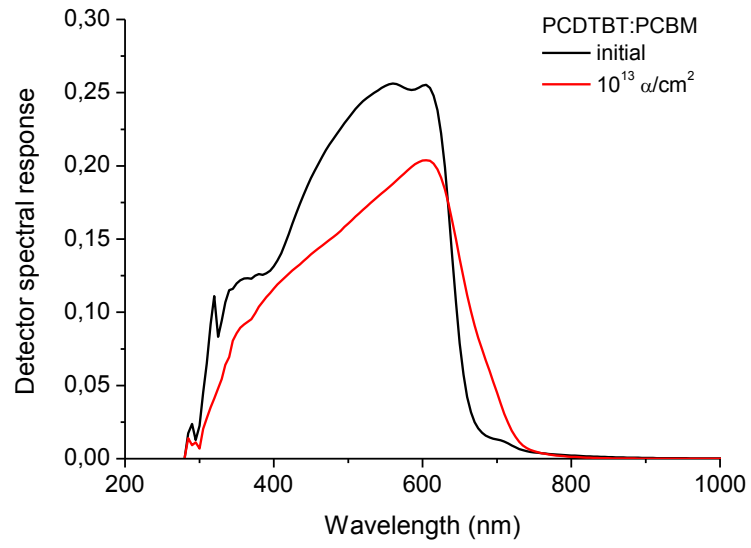


Fig. 10 Variation of the spectral responsivity of an organic solar cell following alpha particles irradiation.